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	First Named Inventor Volki		olkmar SCHULZ	
	Art Unit		2859	
	Examiner Name	Louis M.Arana		
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/LMA/	2	LAZOVIC-STOJKOVIC, J., et al.; Hexagonal Zero Mode Coil: A Single Channel Multi-Coil Design for Small Animal Magnetic Resonance Imaging; 2002; IEEE; pp. 65.									
/LMA/	3	LIN, F., et al.; Quantitative Spectral/Spatial Analysis of Phased Array Coil in Magnetic Resonance Imaging Based on Method of Moment; 1999; IEEE Trans. on Medical Imaging; 18(12)1129-1137.									
/LMA/	4 PRUESSMANN, K.P., et al.; SENSE: Sensitivity Encoding for Fast MRI; 1999; MRM; 42:952-962.										

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/LMA/	5	SODICKSON, D.K., et al.; Recent advances in image reconstruction, coil sensitivity calibration, and coil array design for SMASH and generalized parallel MRI; 2002; MRM; 13:158-163.						
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